

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/783,763	LEE, WHONCHEE	
Examiner	Art Unit	
Kin-Chan Chen	1765	

SEARCHED					
Class	Subclass	Date	Examiner		
438	689	12/2/2005	ксс		
438	693	12/2/05	k 1 c		
45-1	287				
	288				
	443				
451	444				
205	662				
	670				
	671				
205	672	12/2/55	kcc		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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